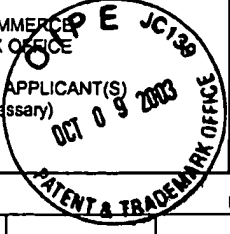


FORM PTO 1449 (modified)  U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE  LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)			ATTY DOCKET NO. <b>03500.010106.5</b>		APPLICATION NO. <b>10/615,995</b>	
			APPLICANT <b>Toshikazu Ohnishi et al.</b>			
			FILING DATE <b>July 10, 2003</b>		GROUP <b>2879</b> <del>NYA</del>	
U.S. PATENT DOCUMENTS						
*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
JW	6,147,449	11/14/00	Iwasaki et al.	313	495	
JW	6,171,162 B1	01/09/01	Iwasaki et al.	445	6	
JW	6,169,356 B1	01/02/01	Ohnishi et al.	313	495	
JW	6,184,610 B1	02/06/01	Shibata et al.	313	309	
JW	6,246,168 B1	06/12/01	Kishi et al.	313	495	
JW	6,384,541 B1	05/07/02	Ohnishi et al.	315	169.3	
FOREIGN PATENT DOCUMENTS						
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
JW	1069826 A	3/10/93	China	H01J	1/30	Abst. & Trans.
JW	1069828 A	3/10/93	China	H01J	19/42	Abst., Trans. & EP 0 513 777
JW	1-031332	02/01/89	Japan	H01J	29/48	Abst.
JW	0 513 777 A2	11/19/92	EPO	H01J	1/30	English
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)						
EXAMINER <b>Joseph Williams</b>			DATE CONSIDERED <b>3/3/04</b>			

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				APPLICANT <b>TOSHIKAZU OHNISHI ET AL.</b>			
				FILING DATE <b>FILED HEREWITH</b>		GROUP <b>2879</b>	

U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
<i>JW</i>		6,348,761 B1	2/02	Nomura et al.	313	495	6/94
<i>JW</i>		4,949,019	8/90	Isaka et al.	445	6	
<i>JW</i>		5,066,883	11/91	Yoshioka et al.	313	309	
<i>JW</i>		5,006,883	11/91	Yoshioka et al.	313	309	
<i>JW</i>		4,954,744	9/90	Suzuki et al.	313	336X	
<i>JW</i>		5,285,129	2/94	Takeda et al.	313	309X	
<i>JW</i>		5,256,936	10/93	Itoh et al.	313	309X	
<i>JW</i>		5,141,460	8/92	Jaskie et al.	313	309X	

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		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
<i>JW</i>		0523702A1	1/93	EPO	_____	_____	Abstract
<i>JW</i>		1283749A	11/89	JAPAN	_____	_____	Abstract
<i>JW</i>		A1309242	12/89	JAPAN	_____	_____	No
<i>JW</i>		536731A1	4/93	EPO	_____	_____	
<i>JW</i>		1-309242	12/89	JAPAN	_____	_____	Translation
<i>JW</i>		0 299 461	1/89	EPO	_____	_____	

EXAMINER <u>Joseph Williams</u>	DATE CONSIDERED <u>3/3/04</u>
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U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		APPLICANT <b>TOSHIKAZU OHNISHI ET AL.</b>	
LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)		FILING DATE <b>FILED HEREWITH</b>	GROUP <b>2879</b>
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)			
<i>JW</i>		"Metal Influence on Switching MIM Diodes", H. Pagnia, et al., Phys. Stat. Sol. (a), 111, 387 (1989)	
<i>JW</i>		"Scanning Tunnelling Microscopic Investigations of Electroformed Planar Metal-Insulator-Metal Diodes," H. Pagnia, N. Sotnik and W. Wirth, Int. J. Electronics, Vol. 69, No. 1, 25-32 (1990)	
<i>JW</i>		"Energy Distribution of Emitted Electrons from Electroformed MIM Structures: The Carbon Island Model," M. Bischoff, H. Pagnia and J. Trinkl, Int. J. Electronics, Vol. 73, No. 5, 1009-1010 (1992)	
<i>JW</i>		"Thin Film Handbook," Committee 131 of Japanese Society for the Promotion of Art and Science	
<i>JW</i>		"On the Electron Emission from Evaporated Thin Au Films," M. Bischoff, R. Holzer and H. Pagnia, Physics Letters, Vol. 62A, No. 7 (October 3, 1977)	
<i>JW</i>		"The Electroforming Process in MIM Diodes," Vol. 85, R. Blessing, H. Pagnia and N. Sotnik, Thin Solid Films, 119-128 (1981)	
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<i>JW</i>		"Water-Influenced Switching in Discontinuous Au Film Diodes," R. Muller and H. Pagnia, Materials Letters, Vol. 2, No. 4A, 283-285 (March 1984)	
<i>JW</i>		"Influence of Organic Molecules on the Current-Voltage Characteristic of Planar MIM Diodes," H. Pagnia, N. Sotnik and H. Strauss, Phy. Stat. Sol., Vol. 90, 771-778 (1985)	
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<i>JW</i>		W.P. Dyke, et al., "Field Emission," Advances in Electronics and Electron Physics, 1956, pp. 90-185	
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<i>JW</i>		C.A. Mead, "Operation of Tunnel-Emission Devices," J. Appl. Phys., Vol. 32, (1961) pp. 646-652	
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		FILING DATE <b>FILED HEREWITH</b>	GROUP <b>2879</b>
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An		G. Dittner, "Electrical Conduction and Electron Emission of Discontinuous Thin Films," Thin Solid Films, 9, (1972) pp. 317-328	
An		H. Hartwell, et al, "Strong Electron Emission From Patterned Tin-Indium Oxide Thin Films," Int'l Electron Devices Meeting (1975) pp. 519-521	
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